

Shenzhen Reflying Electronic Co., Ltd

TEST REPORT

SCOPE OF WORK

SAR ASSESSMENT— AW001-PB, RPB39

REPORT NUMBER

180111017SZN-002

ISSUE DATE

23 January 2018

[REVISED DATE]

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PAGES

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DOCUMENT CONTROL NUMBER

RF Exposure

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Test Report

Applicant: Shenzhen Reflying Electronic Co., Ltd Number: 180111017SZN-002

6 Bldg, GaoXinJian Industrial zone, HePing village, Date: 23 January 2018
Fuyong Town, Bao'an district, Shenzhen,
Guangdong, China.

Sample Description

Product : Keychain Power Bank
Model No. : AW001-PB,RPB39

Brand Name : NA
Electrical Rating : Input: DC 5V, 1A; Output: DC 5V, 1A

Date Received : 11 January 2018

Date Test Conducted : 11 January 2018 to 22 January 2018

Test Requested : Test for compliance with CFR 47 part 1

Test Method : Environmental evaluation and exposure limit according to FCC
CFR 47 part 1, 1.1307(c) and (d), 1.1310

Test Result : Pass

Conclusion : When determining of test conclusion, measurement uncertainty of tests have
been considered.

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Prepared and Checked By:

Approved By:

Sign On File
Surel Guo
Engineer

Kidd Yang
Senior Project Engineer
Date: 24 January 2018

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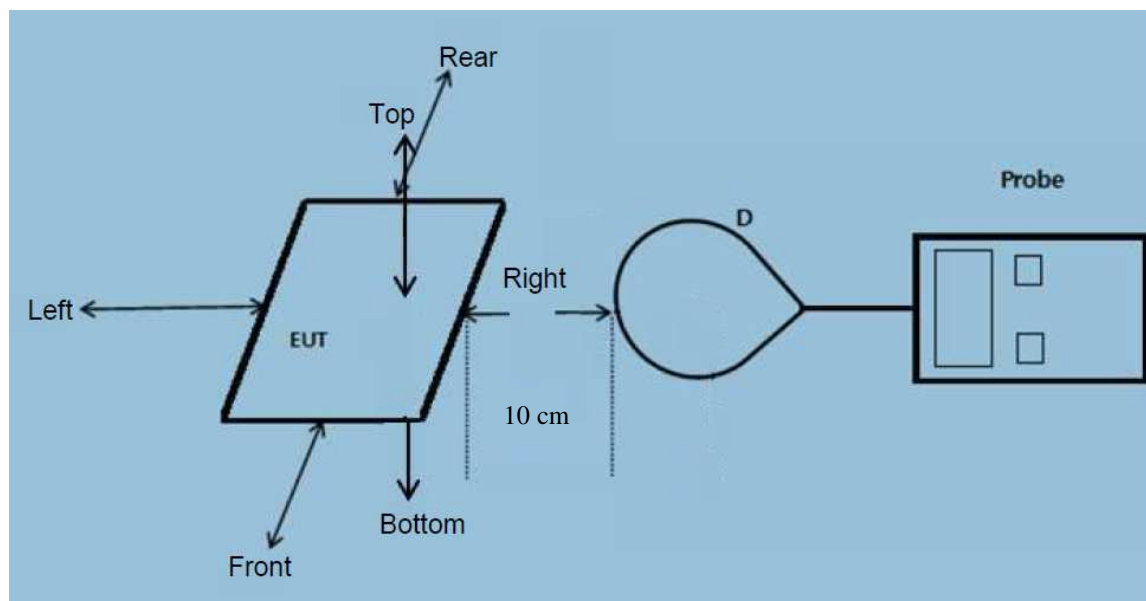
Intertek Testing Service Shenzhen Ltd. Longhua Branch

1F/2F, Building B, QiaoAn Scientific Technology Park, ShangKeng Community, Guanhu Subdistrict, Longhua District, Shenzhen, P.R. China.

Tel: (86 755) 8601 6288 Fax: (86 755) 8601 6751

Test Report

Test Setup Configuration



Note

- The RF exposure test is performed in the shield room.
- The test distance is between the edge of the charger and the geometric centre of probe.
- The Model: RPB39 is the same as the Model: AW001-PB in hardware and electronic aspect. The difference in model number and appearance serve as marketing strategy.

Test Equipment List

Name of instrument	Model	Manufacturer	Cal. Date	Due Date
Exposure Level Tester	ELT-4002304/03	Narda	08-Mar-17	08-Mar-18
Field Probe	HI-6105	ETS	17-Mar-17	17-Mar-18
Laser Data Interface	HI-6113	ETS	17-Mar-17	17-Mar-18

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Reference Limit:

Environmental evaluation and exposure limit according to FCC CFR 47 part 1, 1.1307(c) and (d), 1.1310

According to FCC 1.1310: The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation.

LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency Range (MHz)	Electric field strength (V/m)	Magnetic Field Strength (A/m)	Power Density (mW/cm ²)	Average Time (minutes)
(A) Limits for Occupational/Controlled Exposure				
0.3 – 3.0	614	1.63	(100)*	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3 – 1.34	614	1.63	(100)*	30

Note: * = Plane wave equivalent power density

Test Mode: Charging and power transfer

Test Result:

H-Field Strength at 10 cm from the edges surrounding the EUT

Frequency Range (MHz)	Probe Position A (A/m)	Probe Position B (A/m)	Probe Position C (A/m)	Probe Position D (A/m)	Probe Position E (A/m)	Limits (A/m)
0.550	0.036	0.038	0.040	0.039	0.037	1.63

E-Field Strength at 10 cm from the edges surrounding the EUT

Frequency Range (MHz)	Probe Position A (V/m)	Probe Position B (V/m)	Probe Position C (V/m)	Probe Position D (V/m)	Probe Position E (V/m)	Limits (V/m)
0.550	0.379	0.326	0.393	0.401	0.382	614

Note:

E = electric field strength (V/m), H = magnetic field strength (A/m)

Configuration photo of the test:

H-Field Strength



E-Field Strength

